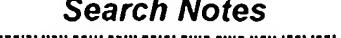


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/005,627	CHANG ET AL.
	Examiner	Art Unit
	Tse Chen	2116

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
713	300	10/11/05	TSG
713	320	10/11/05	TSG